

**HIGH NOISE REDUCTION  
HIGH SPEED ANALOG OUTPUT TYPE  
8 PIN PHOTOCOUPLER**

–NEPOC Series–

**DESCRIPTION**

The PS8602 and PS8602L are 8-pin high speed photocouplers containing a GaAlAs LED on input side and a P-N photodiode and a high speed amplifier transistor on output side on one chip. The PS8602 is in a plastic DIP (Dual In-line Package). The PS8601L is lead bending type (Gull wing) for surface mount.

**FEATURES**

- High common mode transient immunity ( $CM_H, CM_L = \pm 2\,000\text{ kV}/\mu\text{s MIN.}$ )
- High supply voltage ( $V_{CC} = 35\text{ V MAX.}$ )
- High speed response ( $t_{PHL}, t_{PLH} = 0.8\text{ }\mu\text{s MAX.}$ )
- High isolation voltage ( $BV = 5\,000\text{ V}_{r.m.s.}$ )
- TTL, CMOS compatible with a resistor
- For Infrared reflow soldering
- Ordering number of tape product: PS8602L-E3, E4: 1 000 pcs/reel
- Safety standards
  - UL approved: File No. E72422 (S)
  - BSI approved: No. 8004
  - VDE0884 approved (Option) No.91877

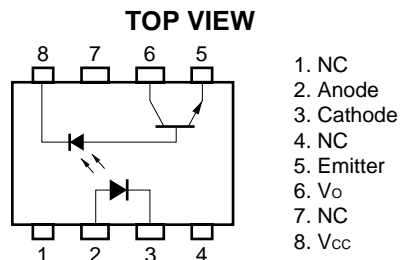
**APPLICATIONS**

- Interface for measurement or control equipment
- Substitutions for relays and pulse transformers

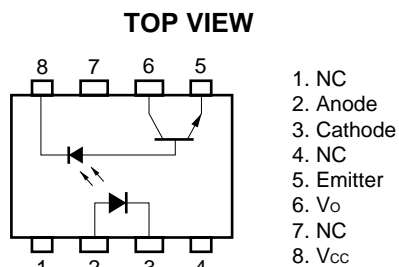
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### DIP Type

## PS8602

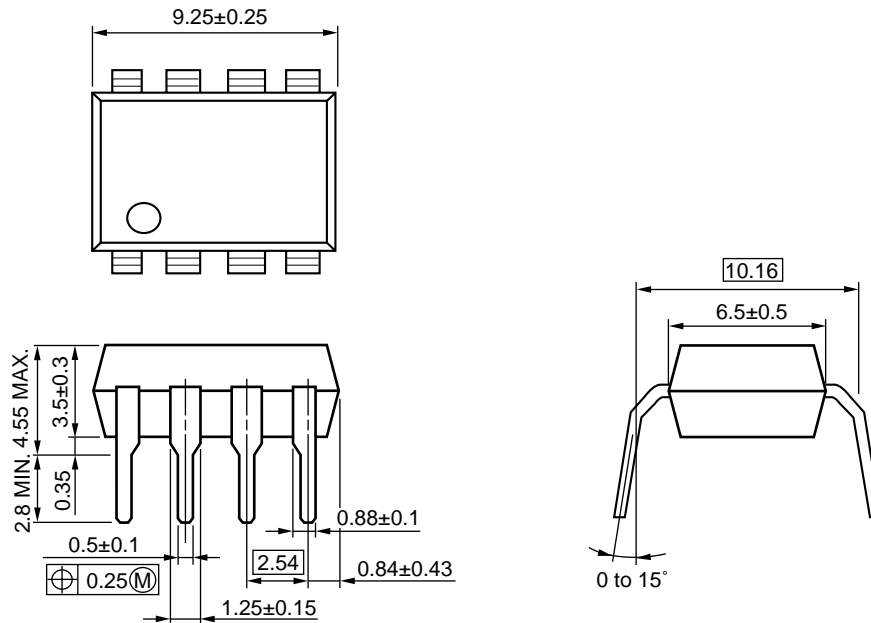


## PS8602L

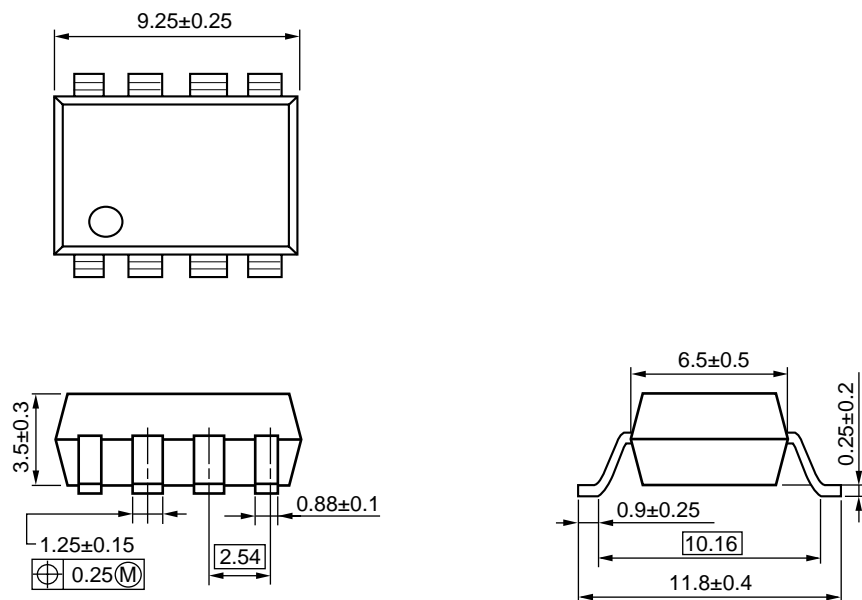


Lead Bending Type For Long Creepage Distance

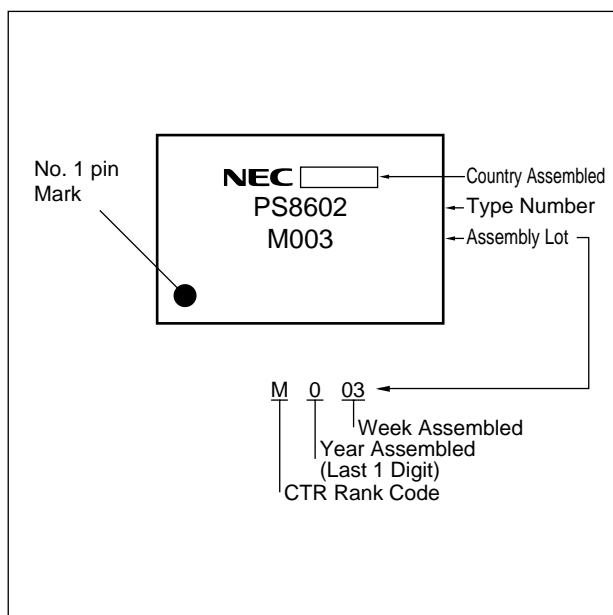
PS8602L1



PS8602L2



# MARKING EXAMPLE



# ORDERING INFORMATION

Part Number	Package	Packing Style	Application Part Number <sup>*1</sup>
PS8602	8-pin DIP	Magazine case 50 pcs	PS8602
PS8602L			PS8602L
PS8602L1			
PS8602L2			
PS8602L-E3		Embossed Tape 1 000 pcs/reel	
PS8602L-E4			
PS8602-V		Magazine case 50 pcs	PS8602
PS8602L-V			PS8602L
PS8602L1-V			
PS8602L2-V			
PS8602L-V-E3		Embossed Tape 1 000 pcs/reel	
PS8602L-V-E4			

\*1 For the application of the Safety Standard, following part number should be used.

## ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25 °C, unless otherwise specified)

Parameter		Symbol	Ratings	Unit
Diode	Forward Current	I <sub>F</sub>	25	mA
	Reverse Voltage	V <sub>R</sub>	5	V
	Power Dissipation	P <sub>D</sub>	45	mW
Detector	Supply Voltage	V <sub>CC</sub>	35	V
	Output Voltage	V <sub>O</sub>	35	V
	Output Current	I <sub>O</sub>	8	mA
	Power Dissipation	P <sub>C</sub>	100	mW
Isolation Voltage <sup>*1</sup>		BV	5 000	Vr.m.s.
Operating Ambient Temperature		T <sub>A</sub>	-55 to +100	°C
Storage Temperature		T <sub>stg</sub>	-55 to +150	°C

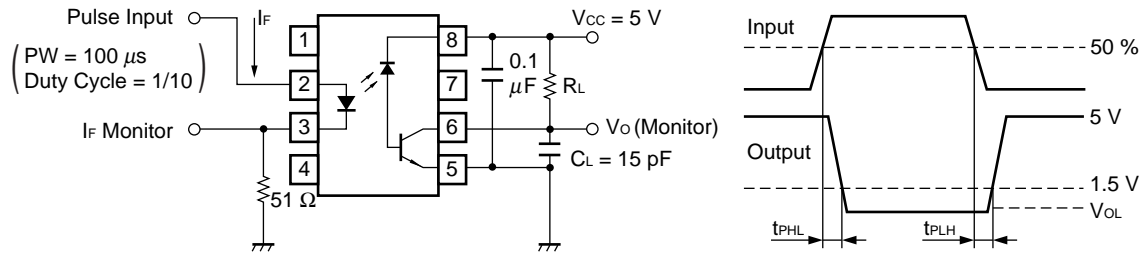
\*1 AC voltage for 1 minute at T<sub>A</sub> = 25 °C, RH = 60 % between input and output.

**ELECTRICAL CHARACTERISTICS (T<sub>A</sub> = 25 °C)**

Parameter		Symbol	Conditions	MIN.	TYP. <sup>1)</sup>	MAX.	Unit
Diode	Forward Voltage	V <sub>F</sub>	I <sub>F</sub> = 16 mA		1.7	2.2	V
	Reverse Current	I <sub>R</sub>	V <sub>R</sub> = 5 V			10	μA
	Forward Voltage Temperature Coefficient	ΔV <sub>F</sub> /ΔT	I <sub>F</sub> = 16 mA		-1.6		mV/°C
	Terminal Capacitance	C <sub>i</sub>	V = 0 V, f = 1 MHz		60		pF
Detector	High Level Output Current	I <sub>OH</sub> (1)	I <sub>F</sub> = 0 mA, V <sub>CC</sub> = V <sub>O</sub> = 5.5 V		3	500	nA
	High Level Output Current	I <sub>OH</sub> (2)	I <sub>F</sub> = 0 mA, V <sub>CC</sub> = V <sub>O</sub> = 35 V			100	μA
	Low Level Output Voltage	V <sub>OL</sub>	I <sub>F</sub> = 16 mA, V <sub>CC</sub> = 4.5 V, I <sub>O</sub> = 1.2 mA		0.1	0.4	V
	Low Level Supply Current	I <sub>CCL</sub>	I <sub>F</sub> = 16 mA, V <sub>O</sub> = Open, V <sub>CC</sub> = 35 V		50		μA
	High Level Supply Current	I <sub>CCH</sub>	I <sub>F</sub> = 0 mA, V <sub>O</sub> = Open, V <sub>CC</sub> = 35 V		0.01	1	μA
Coupled	Current Transfer Ratio	CTR	I <sub>F</sub> = 16 mA, V <sub>CC</sub> = 4.5 V, V <sub>O</sub> = 0.4 V	15			%
	Isolation Resistance	R <sub>I-O</sub>	V <sub>I-O</sub> = 1 kV <sub>DC</sub>	10 <sup>11</sup>			Ω
	Isolation Capacitance	C <sub>I-O</sub>	V = 0 V, f = 1 MHz		0.7		pF
	Propagation Delay Time (H → L) <sup>2)</sup>	t <sub>PHL</sub>	I <sub>F</sub> = 16 mA, V <sub>CC</sub> = 5 V, R <sub>L</sub> = 1.9 kΩ		0.5	0.8	μs
	Propagation Delay Time (L → H) <sup>2)</sup>	t <sub>PLH</sub>	I <sub>F</sub> = 16 mA, V <sub>CC</sub> = 5 V, R <sub>L</sub> = 1.9 kΩ		0.3	0.8	μs
	Common Mode Transient Immunity at High Level Output <sup>3)</sup>	CM <sub>H</sub>	I <sub>F</sub> = 0 mA, V <sub>CM</sub> = 400 V R <sub>L</sub> = 4.1 kΩ	-2 000			V/μs
	Common Mode Transient Immunity at Low Level Output <sup>3)</sup>	CM <sub>L</sub>	I <sub>F</sub> = 16 mA, V <sub>CM</sub> = 400 V R <sub>L</sub> = 4.1 kΩ	2 000			V/μs

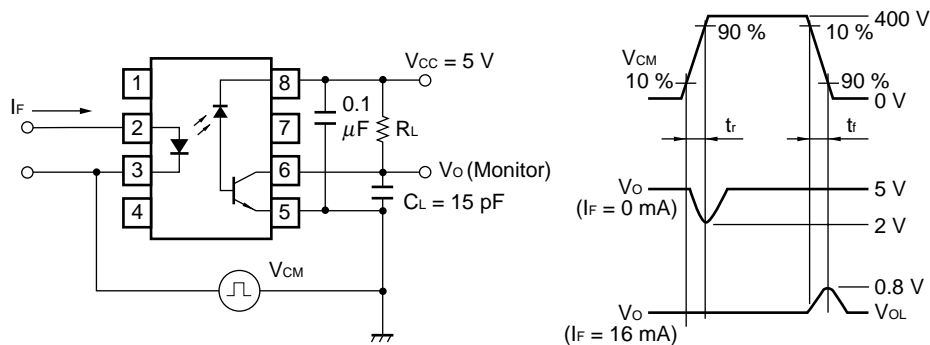
\*1 Typical values at  $T_A = 25^\circ\text{C}$

\*2 Test circuit for propagation delay time



$C_L$  includes probe and stray wiring capacitance

\*3 Test circuit for common mode transient immunity

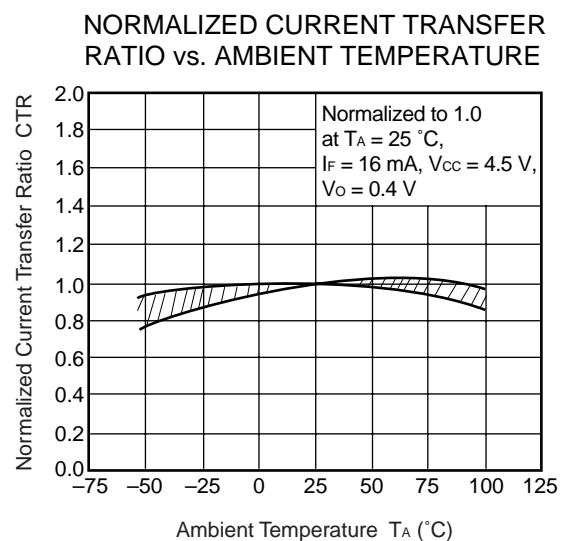
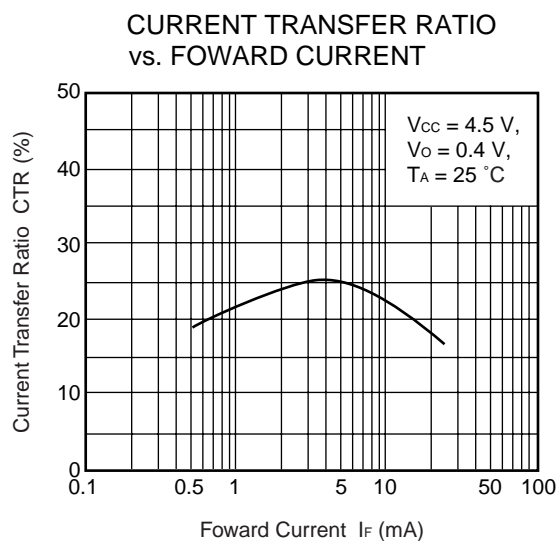
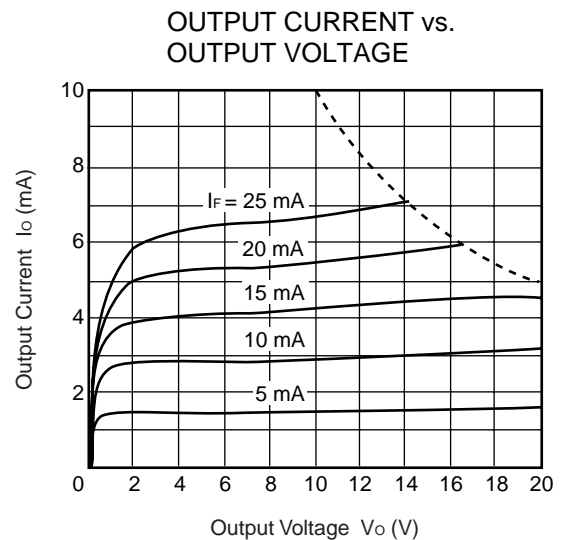
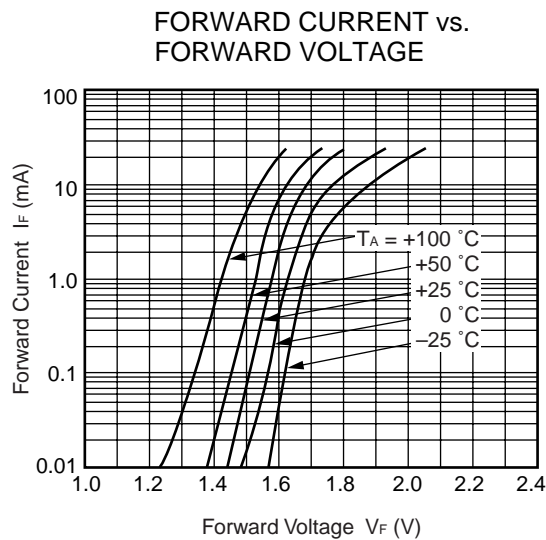
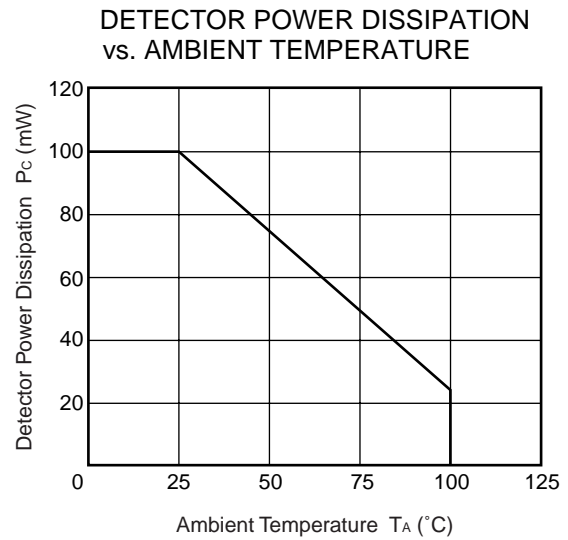
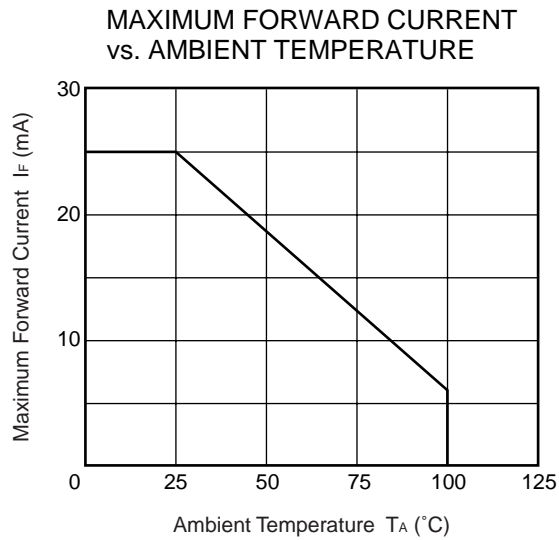


$C_L$  includes probe and stray wiring capacitance

## USAGE CAUTIONS

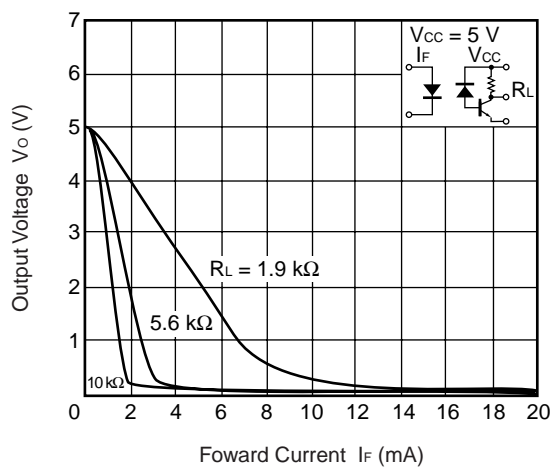
1. This product is weak for static electricity by designed with high-speed integrated circuit so protect against static electricity when handling.
2. By-pass capacitor of more than  $0.1\ \mu\text{F}$  is used between  $V_{CC}$  and GND near device. Also, ensure that the distance between the leads of the photocoupler and capacitor is no more than 10 mm.
- ★ 3. Avoid storage at a high temperature and high humidity.

**TYPICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ , unless otherwise specified)**

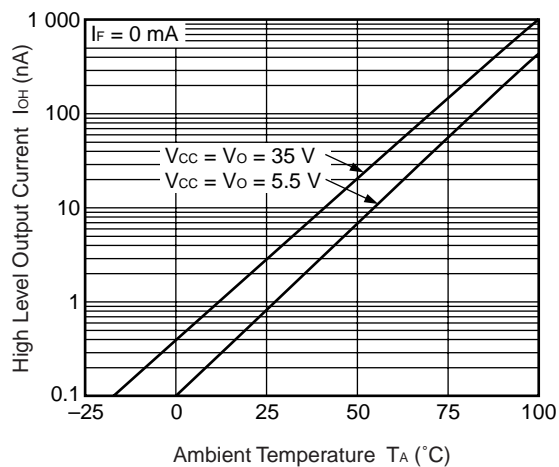




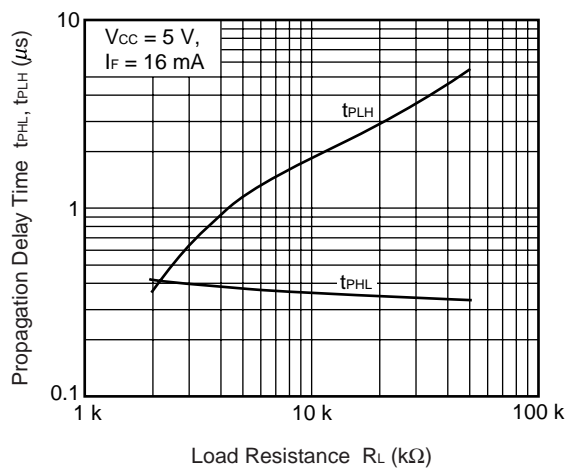
OUTPUT VOLTAGE vs.  
FOWARD CURRENT



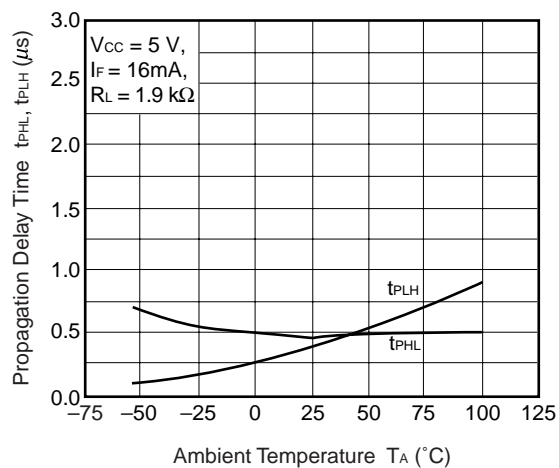
HIGH LEVEL OUTPUT CURRENT  
vs. AMBIENT TEMPERATURE



PROPAGATION DELAY TIME,  
vs. LORD RESISTANCE



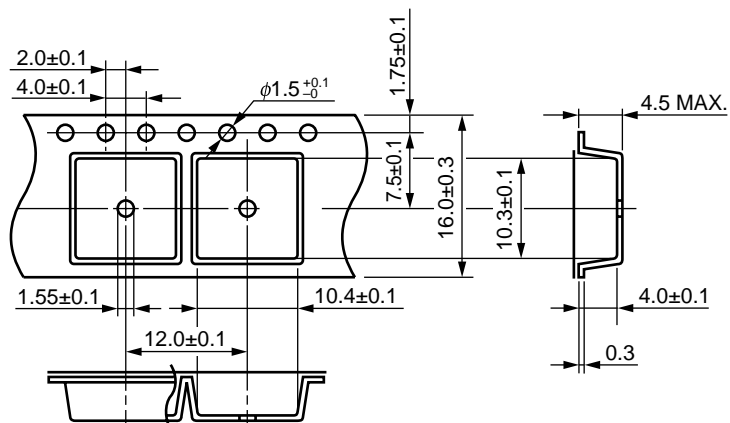
PROPAGATION DELAY TIME,  
vs. AMBIENT TEMPERATURE



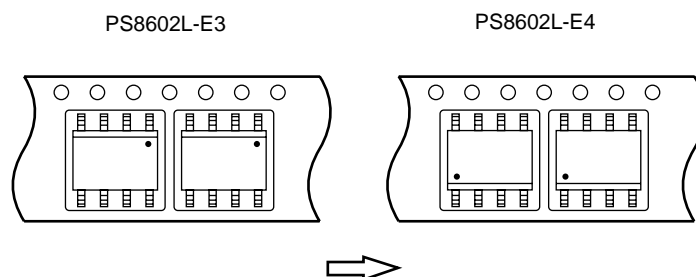
**Remark** The graphs indicate nominal characteristics.

★ TAPING SPECIFICATIONS (UNIT: mm)

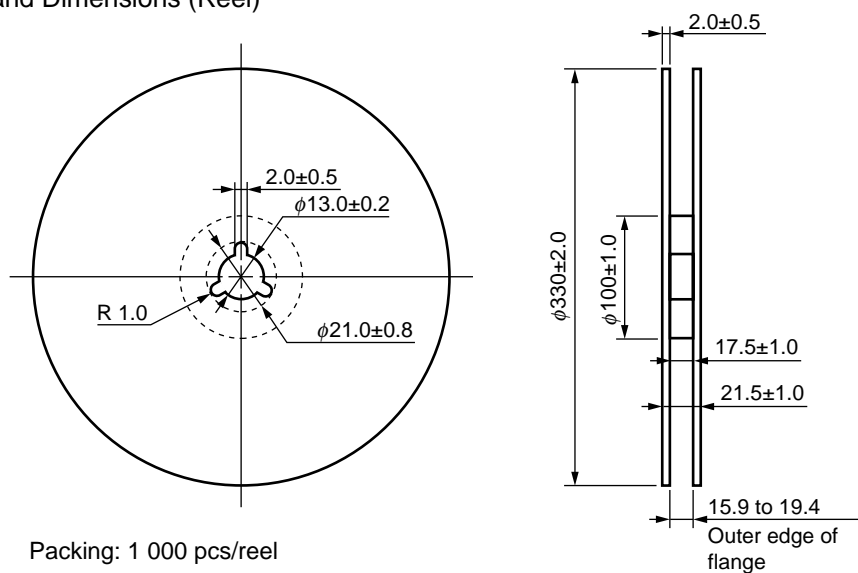
Outline and Dimensions (Tape)



Tape Direction



Outline and Dimensions (Reel)



Packing: 1 000 pcs/reel

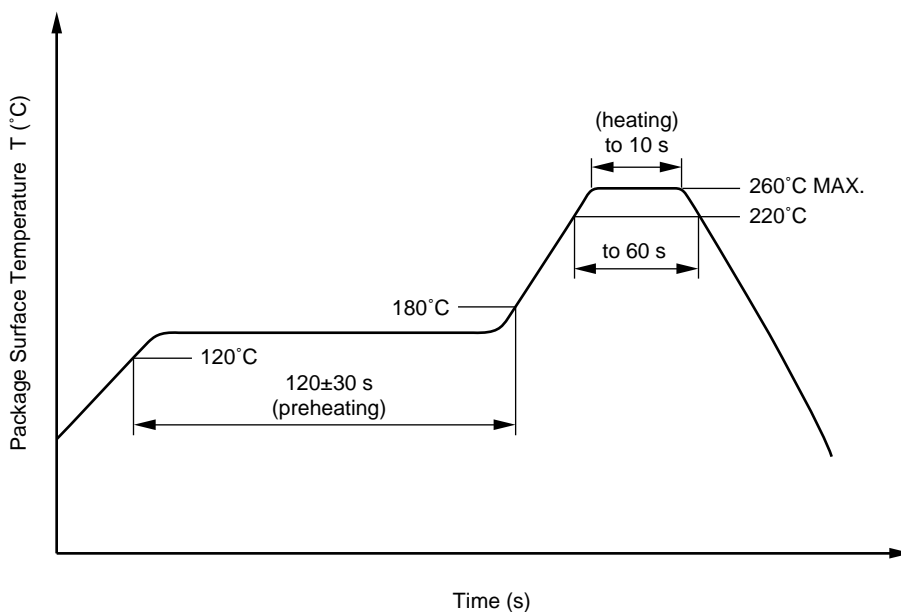
★ NOTES ON HANDLING

1. Recommended soldering conditions

(1) Infrared reflow soldering

- Peak reflow temperature 260°C or below (package surface temperature)
- Time of peak reflow temperature 10 seconds or less
- Time of temperature higher than 220°C 60 seconds or less
- Time to preheat temperature from 120 to 180°C 120±30 s
- Number of reflows Three
- Flux Rosin flux containing small amount of chlorine (The flux with a maximum chlorine content of 0.2 Wt% is recommended.)

Recommended Temperature Profile of Infrared Reflow



(2) Wave soldering

- Temperature 260°C or below (molten solder temperature)
- Time 10 seconds or less
- Preheating conditions 120°C or below (package surface temperature)
- Number of times One (Allowed to be dipped in solder including plastic mold portion.)
- Flux Rosin flux containing small amount of chlorine (The flux with a maximum chlorine content of 0.2 Wt% is recommended.)

(3) Cautions

- Fluxes  
Avoid removing the residual flux with freon-based and chlorine-based cleaning solvent.

2. Cautions regarding noise

Be aware that when voltage is applied suddenly between the photocoupler's input and output or between collector-emitters at startup, the output side may enter the on state, even if the voltage is within the absolute maximum ratings.

SPECIFICATION OF VDE MARKS LICENSE DOCUMENT (VDE0884)

Parameter	Symbol	Speck	Unit
Application classification (DIN VDE 0109) for rated line voltages $\leq 300$ V <sub>r.m.s.</sub> for rated line voltages $\leq 600$ V <sub>r.m.s.</sub>		IV III	
Climatic test class (DIN IEC 68 Teil 1/09.80)		55/100/21	
Dielectric strength maximum operating isolation voltage Test voltage (partial discharge test, procedure a for type test and random test) $U_{pr} = 1.2 \times U_{IORM}$ , $P_d < 5$ pC	$U_{IORM}$ $U_{pr}$	890 1 068	V <sub>peak</sub> V <sub>peak</sub>
★ Test voltage (partial discharge test, procedure b for all devices) $U_{pr} = 1.6 \times U_{IORM}$ , $P_d < 5$ pC	$U_{pr}$	1 424	V <sub>peak</sub>
Highest permissible overvoltage	$U_{TR}$	8 000	V <sub>peak</sub>
Degree of pollution (DIN VDE 0109)		2	
Clearance distance		> 7.0	mm
Creepage distance		> 7.0	mm
Comparative tracking index (DIN IEC 112/VDE 0303 part 1)	CTI	175	
Material group (DIN VDE 0109)		III a	
Storage temperature range	T <sub>stg</sub>	-55 to +150	°C
Operating temperature range	T <sub>A</sub>	-55 to +100	°C
Isolation resistance, minimum value V <sub>IO</sub> = 500 V dc at T <sub>A</sub> = 25 °C V <sub>IO</sub> = 500 V dc at T <sub>A</sub> MAX. at least 100 °C	R <sub>is</sub> MIN. R <sub>is</sub> MIN.	10 <sup>12</sup> 10 <sup>11</sup>	Ω Ω
Safety maximum ratings (maximum permissible in case of fault, see thermal derating curve) Package temperature Current (input current I <sub>F</sub> , P <sub>si</sub> = 0) Power (output or total power dissipation) Isolation resistance V <sub>IO</sub> = 500 V dc at T <sub>A</sub> = 175 °C (T <sub>si</sub> )	T <sub>si</sub> I <sub>si</sub> P <sub>si</sub> R <sub>is</sub> MIN.	175 400 700 10 <sup>9</sup>	°C mA mW Ω

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M8E 00.4-0110

**SAFETY INFORMATION ON THIS PRODUCT**

<div data-bbox="188 277 280 304">Caution</div> <div data-bbox="300 277 448 302">GaAs Products</div>	<p>The product contains gallium arsenide, GaAs. GaAs vapor and powder are hazardous to human health if inhaled or ingested.</p> <ul style="list-style-type: none"> <li>• Do not destroy or burn the product.</li> <li>• Do not cut or cleave off any part of the product.</li> <li>• Do not crush or chemically dissolve the product.</li> <li>• Do not put the product in the mouth.</li> </ul> <p>Follow related laws and ordinances for disposal. The product should be excluded from general industrial waste or household garbage.</p>
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► For further information, please contact

**NEC Compound Semiconductor Devices, Ltd.**

5th Sales Group, Sales Division TEL: +81-44-435-1588 FAX: +81-44-435-1579 E-mail: salesinfo@csd-nec.com

**NEC Compound Semiconductor Devices Hong Kong Limited**

Hong Kong Head Office TEL: +852-3107-7303 FAX: +852-3107-7309  
 Taipei Branch Office TEL: +886-2-8712-0478 FAX: +886-2-2545-3859  
 Korea Branch Office TEL: +82-2-558-2120 FAX: +82-2-558-5209

**NEC Electronics (Europe) GmbH** <http://www.ee.nec.de/>

TEL: +49-211-6503-01 FAX: +49-211-6503-487

**California Eastern Laboratories, Inc.** <http://www.cel.com/>

TEL: +1-408-988-3500 FAX: +1-408-988-0279